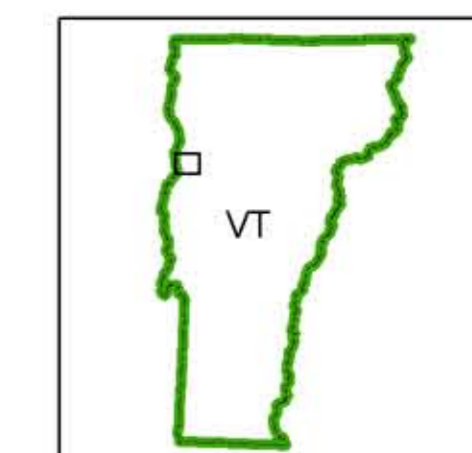


Legend

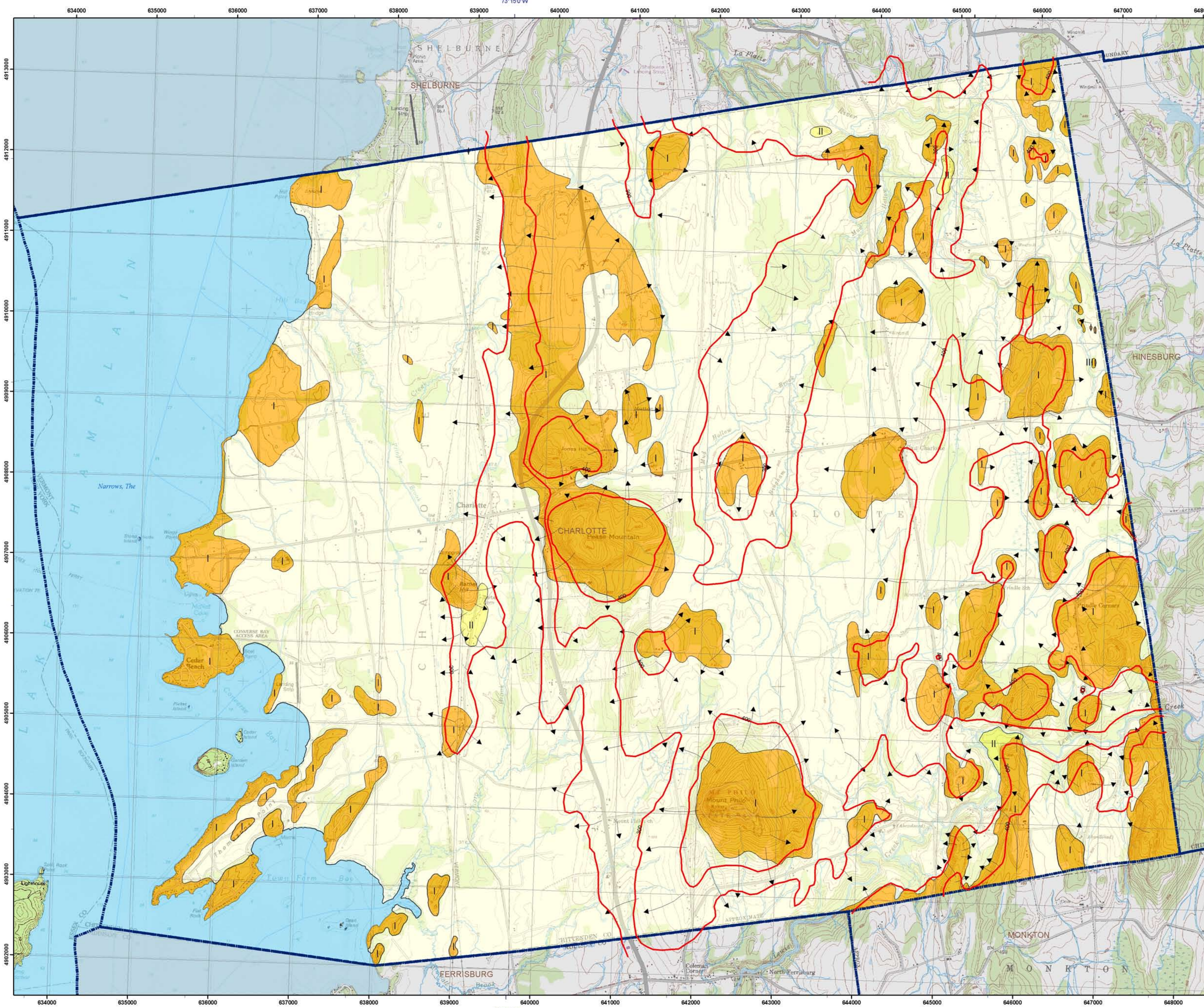
Recharge Potential to Bedrock Aquifer

- I** Higher recharge potential: Primarily located in areas of thin till and exposed bedrock outcrops where water can infiltrate into bedrock through fractures, some of which have been solutionally enlarged. Solution enlarged fractures are common in limestones and marbles in the northeast portion of Charlotte.
- II** Moderate recharge potential: Characterized by unconsolidated sediment with some permeability which allows water to infiltrate to the underlying bedrock.
- III** Lower recharge potential: characterized by thin to thick deposits of impermeable unconsolidated sediment such as clay, silt and/or thick clay-rich till overlying the bedrock. The material tends to impede recharge of bedrock and surficial aquifers below.
- Piezometric Surface (refer to Plate 2); Contour interval is 100 ft
- Inferred Flow Lines (refer to Plate 2)
- Town Boundaries

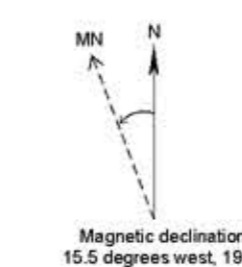
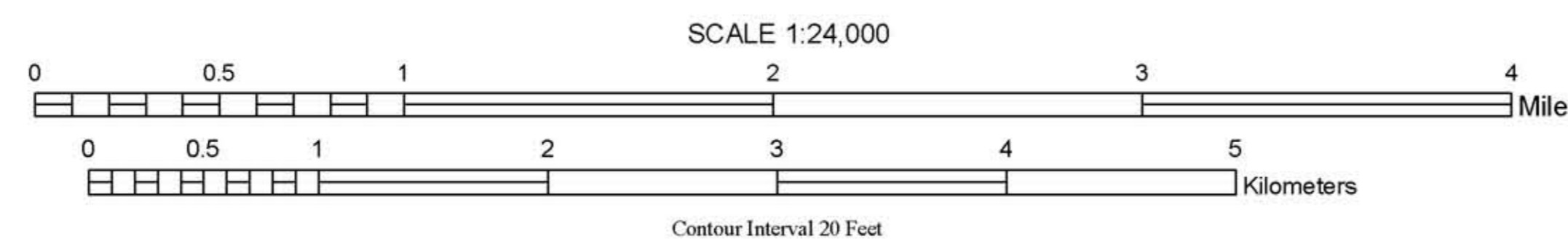


LOCATION MAP

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 Vermont Geological Survey
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Base map from U.S. Geological Survey.
 Quadrangle names printed in blue.
 Coordinate System: Vermont State Plane, meters, NAD 83.
 Geographic coordinates shown at topo corners are in NAD 83.
 Grid overlay on map is Universal Transverse Mercator,
 Zone 18N, NAD 27.
 Date: May 2010



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RECHARGE POTENTIAL TO BEDROCK AQUIFER, CHARLOTTE, VERMONT

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2010